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John G. Jones  
Lirong Sun  
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Tyson C. Back  
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John G. Jones,$^{a,*}$ Lirong Sun,$^b$ Neil R. Murphy,$^a$ Tyson C. Back,$^c$ Matthew A. Lange,$^c$ Jessica L. Remmert,$^c$ P. Terrence Murray,$^d$ and Rachel Jakubiak$^a$

$^a$Air Force Research Laboratory, 3005 Hobson Way, Wright-Patterson AFB, Ohio 45433
$^b$General Dynamics Information Technology, 5100 Springfield Road, Dayton, Ohio 45431
$^c$Universal Technology Corporation, 1270 North Fairfield Road, Dayton, Ohio 45532
$^d$University of Dayton Research Institute, 300 College Park, Dayton, Ohio 45469

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*Address all correspondence to: John G. Jones, E-mail: john.jones.66@us.af.mil